



U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

**SUPPLEMENTAL
INFORMATION DISCLOSURE STATEMENT**
(Use several sheets if necessary)

ATTY. DOCKET NO.
854163.414

APPLICATION NO.
10/824,631

APPLICANT
Fabio Pellizzer

FILING DATE
April 14, 2004

GROUP ART UNIT
2815

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	5,789,277	08/04/98	Zahorik et al.	438	95	
	AB	5,814,527	09/29/98	Wolstenholme et al.	438	5	
	AC	5,952,671	09/14/99	Reinberg et al.	257	3	
	AD	5,970,336	10/19/99	Wolstenholme et al.	438	238	
	AE	6,031,287	02/29/00	Harshfield	257	734	
	AF	6,238,946	05/29/01	Ziegler	438	50	
	AG	6,313,604	11/06/01	Maimon et al.	438	95	
	AH	6,541,333	04/01/03	Shukuri et al.	438	243	
	AI	6,613,604	09/02/03	Maimon et al.	438	95	
	AJ	6,617,192	09/09/03	Lowrey et al.	438	95	
	AK	6,750,079	06/15/04	Lowrey et al.	438	95	
	AL	6,759,267	07/06/04	Chen	438	95	

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
	AM	WO 00/57498	09/28/00	WIPO		
	AN					
	AO					
	AP					

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	AQ	Palun, L. et al., "Fabrication of Single Electron Devices by Hybrid (E-Beam/DUV) Lithography," Microelectronic Engineering 53, pp. 167-170, 2000.
	AR	

EXAMINER

JOSEPH H. NGUYEN

DATE CONSIDERED

4/7/06

* EXAMINER: Initial if reference considered, whether or not criteria is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant(s).

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)	ATTY. DOCKET NO. 854163.414	APPLICATION NO. 10/824,631
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*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	BA	6,777,705	08/17/04	Reinberg et al.	257	2	
	BB	6,943,365	09/13/05	Lowrey et al.	257	3	
	BC	6,972,430	12/06/05	Casagnade et al.	257	4	
	BD	6,969,866	11/29/05	Lowrey et al.	257	3	
	BE	2002/0070401	06/13/02	Takeuchi et al.	257	296	
	BF	2003/0075778	04/24/03	Klersy	257	536	
	BG	2003/0219924	11/27/03	Bez et al.	438	102	
	BH	2004/0113181	01/22/04	Klebanoff et al.	134	2	
	BI	2004/0166604	08/26/04	Ha et al.	438	102	
	BJ	2004/0245603	12/09/04	Lowrey et al.	257	536	

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
	BK					
	BL					
	BM					
	BN					
	BO					

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	BP	
	BQ	
	BR	

EXAMINER

JOSEPH H. RAYEN

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